

FIG. 1
(PRIOR ART)

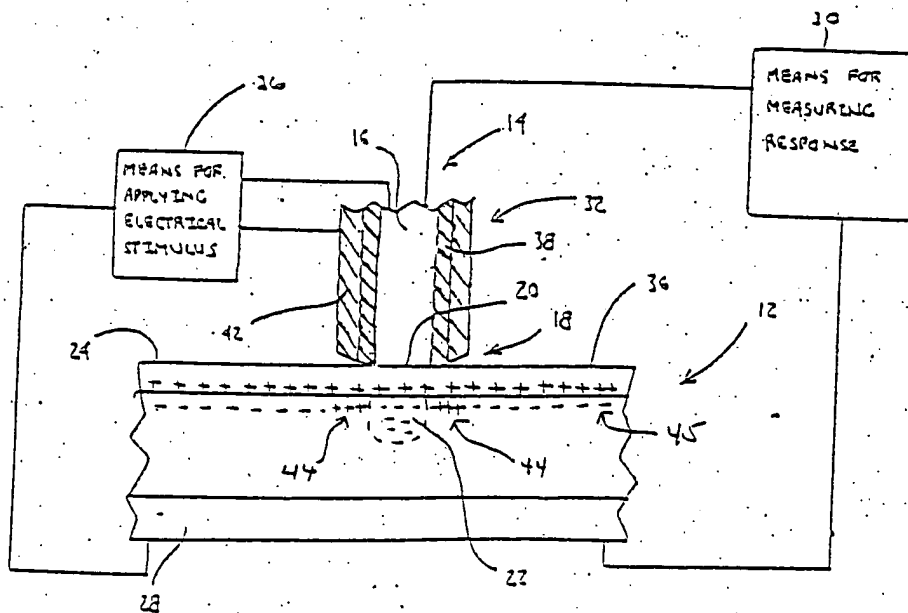


FIG. 4

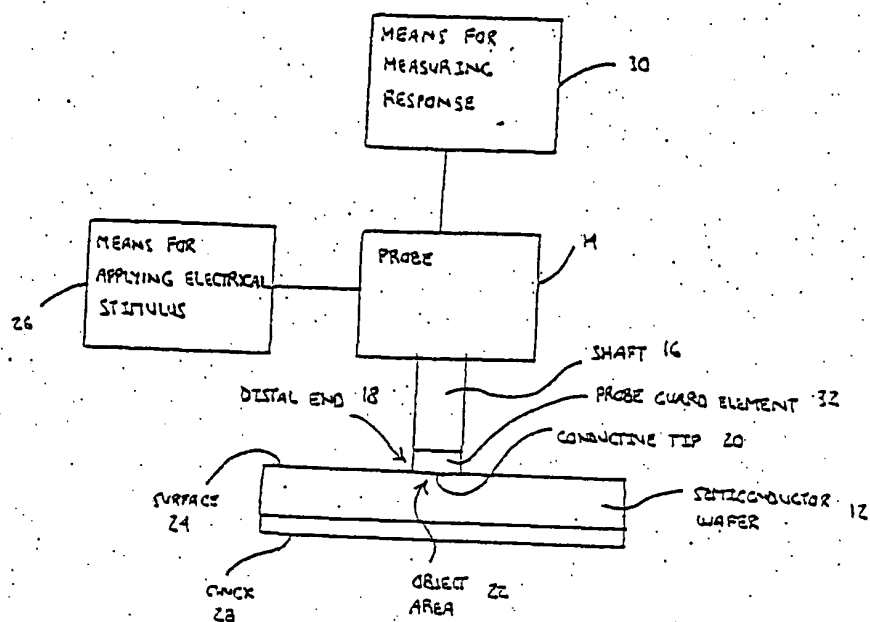


FIG. 2

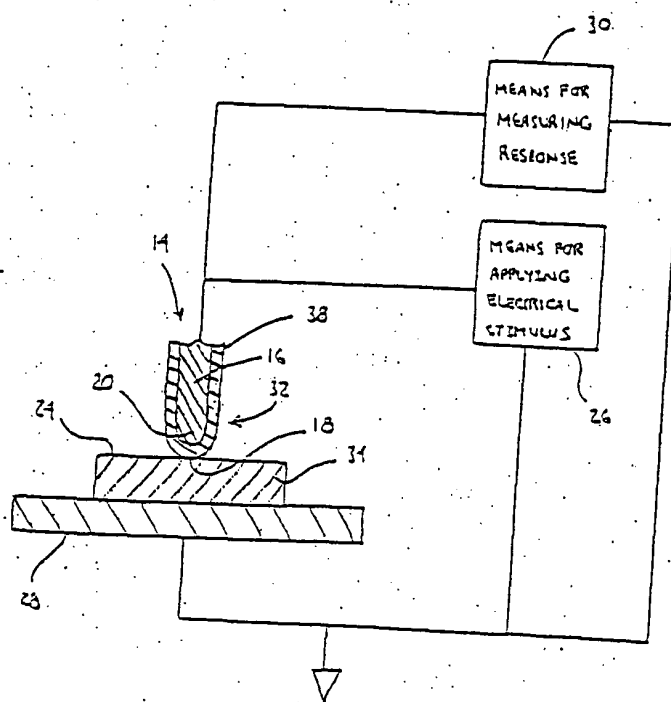


FIG. 3

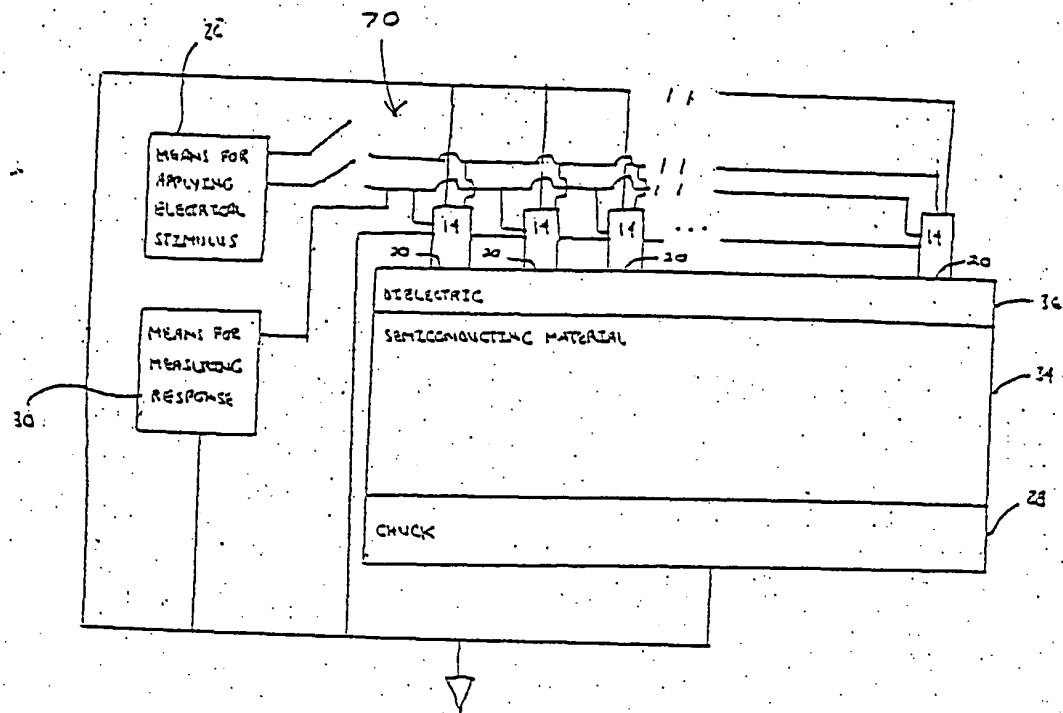


FIG. 5

Inventor: William H. Howland
"APPARATUS FOR DETERMINING DOPING CONCENTRATION OF A SEMICONDUCTOR WAFER"
Attorney Docket No.: 1880-031286

